Search Notes



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Applicant(s)/Patent Under Reexamination

INOUE ET AL.

Examiner

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
379	100.07,100.04	11/20/2007	JB
358	468,407,402,404,518,1.18,1.15,402,1.15,403,1.14,1.13, 1.12	11/20/2007	JB
705	2,58,51,75,73,26,,71,43,64	11/20/2007	JB
348	231.9, 552,239,231.3,	11/20/2007	JB
380	54	11/20/2007	JB
709	206,223	11/20/2007	JB
715	839	11/20/2007	JB
718	102	11/20/2007	JB
382	233,100	11/20/2007	JB
400	61	11/20/2007	JB
700	241	11/20/2007	JB
434	350	11/20/2007	JB

SEARCH NOTES

Search Notes	Date	Examiner		
EAST	11/19/2007	JB		
EAST	11/20/2007	JB		
CONSULTED WITH HAI TRAN	11/19/2007	JB		

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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